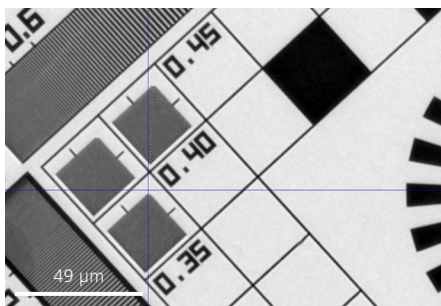
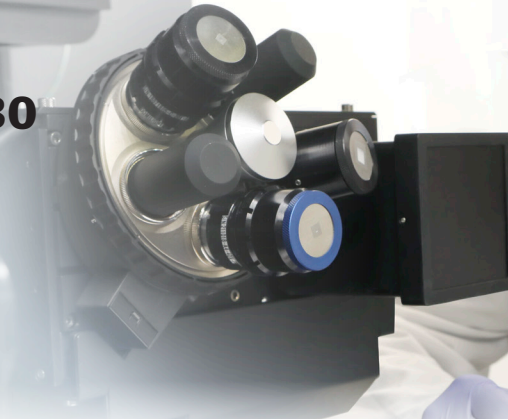
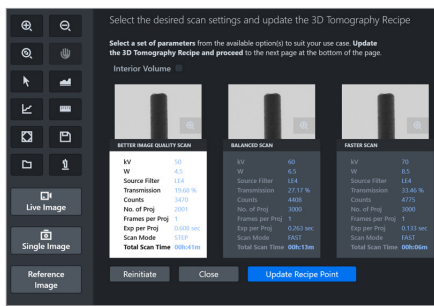


Perfect tomographies. Every sample. Every user. Every time.

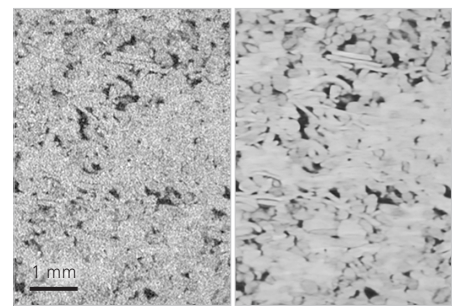
ZEISS VersaXRM 730



40x-P resolution of 450 nm collected at 30 kV source voltage.



ZEN navx guides users through automated workflows with intelligent system insights to deliver results more easily and efficiently.



Use FAST Mode to rapidly acquire data and the AI based DeepRecon Pro to improve image quality. Sandstone captured in 39 seconds, reconstruction showing standard FDK (left) and AI (right) comparison.

Optimize visibility with higher resolution & performance

Resolution performance is about more than just highest specified resolution. With today's dynamic research demands, you want to achieve high-resolution 3D imaging across the widest range of sample types. ZEISS VersaXRM® 730, with the exclusive 40x-Prime (40x-P) objective, enables you to push the limits of submicron imaging with unparalleled resolution performance of 450-500 nm across the full range of ZXR-1 X-ray source voltage, from 30 kV to 160 kV. Purpose-built by ZEISS for the demands of XRM imaging, ZXR-1 is the source for future innovation. AI allows you to gain deeper insights and extend your capabilities by improving image quality and expanding your field of view.

Improve productivity & accessibility with human-centered design

The physics of X-ray imaging can be complex, so ZEISS XRM researchers studied user habits, dove into their challenges and employed human-centered design (HCD) principles to develop the award-winning ZEN navx® guidance and control system for VersaXRM. ZEN navx enables even the newest user in a busy environment to be immediately productive doing advanced 3D X-ray microscopy, greatly reducing the burden of training. It also allows your experienced users to explore the full versatility of the platform. ZEN navx File Transfer Utility (FTU) automatically transfers data from the microscope to where you need it, when you need it.

Achieve efficient, fast targeting with end-to-end 3D navigation

With VersaXRM 730, you can now navigate in 3D, image in 3D, and analyze in 3D with an innovative and immersive end-to-end experience. Innovation in throughput and image quality performance across both hardware and software help you achieve maximum impact with your research.

- Acquire more data in less system time
- Get the right data the first time with the intuitive ZEN navx interface
- Achieve rapid turnaround on imaging or sample inspection with one-minute tomographies using FAST Mode and Flat Panel Extension (FPX)
- Pinpoint images with confidence using Volume Scout for true 3D feature targeting



Seeing beyond

VersaXRM: The world's most proven X-ray microscope

42+

Countries publishing VersaXRM papers

4

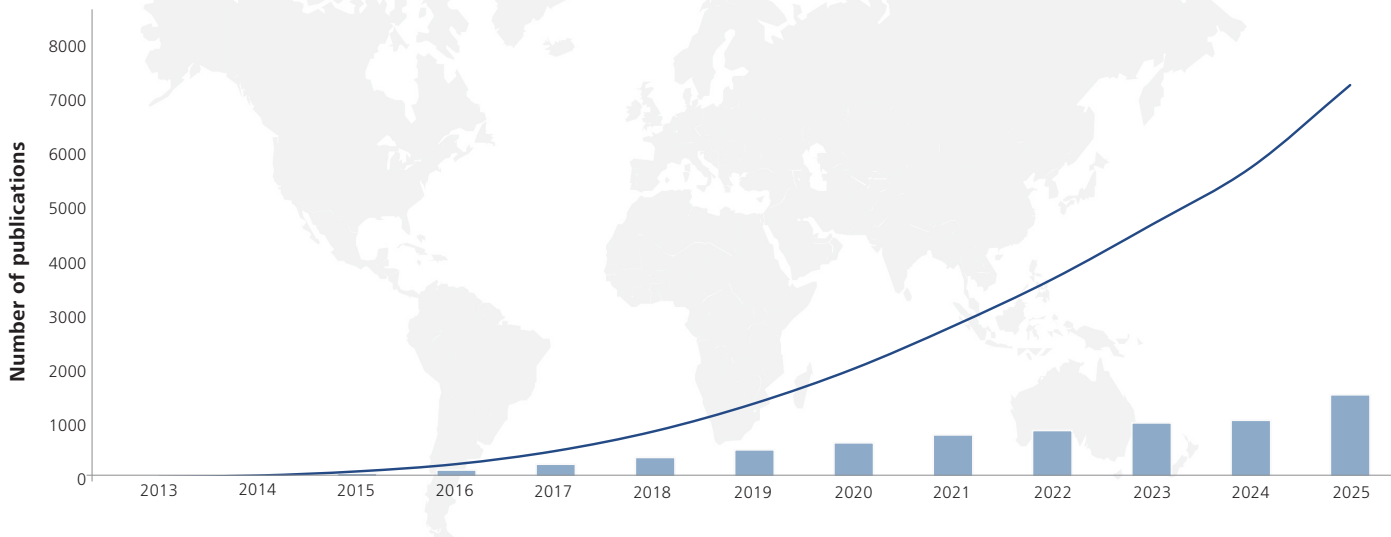
On average, new ZEISS VersaXRM publications *every day*

7270

VersaXRM publications *and counting...*

400+

Unique institutions listed as authors or co-authors



Imaging	ZEISS VersaXRM 730	ZEISS VersaXRM 615	ZEISS Xradia 515 Versa
Spatial resolution ^[a]	450 nm	500 nm	500 nm
Resolution performance ^[b] (ZEISS Resolution Target at 160 kV/LE6, equivalent to 1.3 mm Al and 40x-P objective)	500 nm		
Resolution at a Distance (RaAD) ^[c] (50 mm working distance)		1.0 µm	1.0 µm
Resolution performance at a distance (ZEISS Resolution Target at 140 kV/LE4, equivalent to 0.6 mm Al)	700 nm @ 50 mm 750 nm @ 100 mm		
Minimum achievable voxel ^[d] (Voxel size at sample at maximum magnification)	40 nm	40 nm	40 nm
X-ray source	ZXR-1	High voltage source	High voltage source
Architecture	Sealed transmission, fast activation	Sealed transmission, fast activation	Sealed transmission, fast activation
Voltage range	30 – 160 kV	30 – 160 kV	30 – 160 kV
Maximum output	25 W	25 W	10 W

Detector system			
ZEISS X-ray microscopes feature an innovative detector turret with multiple objectives at different magnifications. Each objective features optimized scintillators that deliver the highest absorption contrast details.			
Standard objectives	0.4x, 4x, 20x	0.4x, 4x, 20x	0.4x, 4x, 20x
Optional objectives	40x-P, Flat Panel Extension (FPX)	40x, Flat Panel Extension (FPX)	40x, Flat Panel Extension (FPX)

Stages
Sample stage load capacity, 25 kg; travel (x-50 mm, y-100mm, z-50 mm)

Features	ZEISS VersaXRM 730	ZEISS VersaXRM 615	ZEISS Xradia 515 Versa
Control system	ZEN navx	ZEN navx	Scout-and-Scan
Scout-and-Zoom	Volume Scout in ZEN navx	Volume Scout in ZEN navx	Manual or with 3D World ZEISS edition
Flat Panel Extension (FPX)	Optional FPX: FAST or STEP mode	Optional FPX: FAST or STEP mode	Optional FPX: STEP Mode only
Wide field mode	4x		
Vertical stitch	■	■	■
XRM Python API	■	■	■
ZEISS SmartShield	SmartShield, SmartShield Lite	SmartShield, SmartShield Lite	SmartShield
Source Filters	Automated Filter Changer (AFC) 24-filter capacity, 12 standard filters included	Single manual filter holder, 12 standard filters included	
High Aspect Ratio Tomography (HART)	■		
Dual Scan Contrast Visualizer (DSCoVer)	■		
ZEISS LabDCT for Diffraction Contrast Tomography	Optional		
GPU CUDA-based reconstruction	Dual	Dual	Dual
Secondary high performance workstation	■	■	Optional 1 year or perpetual license
ZEISS Autoloader	Optional	Optional	Optional
ZEISS Versa In Situ Interface Kit	Optional	Optional	Optional
ZEISS DeepRecon Pro	Included with 2-year license	Included with 2-year license	Optional
ZEISS DeepScout	Optional	Optional	Optional
ZEISS PhaseEvolve	Optional	Optional	Optional
ZEISS MARS	Optional	Optional	Optional
ZEISS OptiRecon	Optional	Optional	Optional
ZEN AI Toolkit with Intellesis	Optional	Optional	Optional
3D World ZEISS edition from Dragonfly	Optional	Optional	Optional

[a] Spatial resolution measured with ZEISS XRM 2D resolution target, normal field mode, optional 40x-P (730) or 40x (615, 515).
 [b] Resolution performance measured with ZEISS XRM 2D resolution target, normal field mode, optional 40x-P objective.
 [c] RaAD working distance is defined as clearance around axis of rotation (sample radius). Resolution is measured with ZEISS 2D resolution target.
 [d] Voxel is a geometric term that contributes to but does not determine resolution and is provided here only for comparison. ZEISS specifies resolution via spatial resolution for Versa XRM, the true overall measurement of instrument resolution.



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